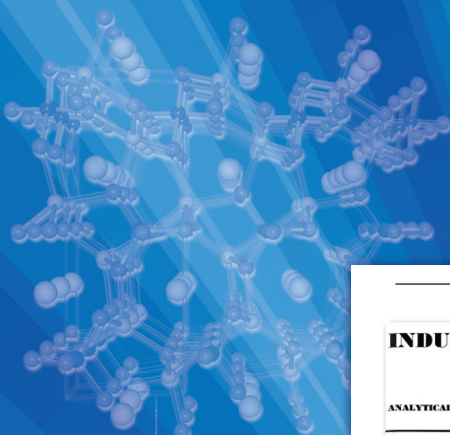


Powder Diffraction PDJ

Journal of Materials Characterization



1938

1941

2017

3D structure and Bonds

SAED and EBSD simulations

XRD, ED, ND ring pattern simulations

Wavelength options

- Co Ka1 1.78896 Å
- Cu Ka(Avg) 1.54184 Å
- Cu Ka1 1.54056 Å
- Mo Ka1 0.70930 Å
- Ag Ka1 0.55941 Å
- Other X-ray (Å)
- CW Neutron (Å)
- TOF Neutron

Raw data PD3 patterns

Simulated diffraction patterns

X-ray

Synchrotron

Neutron CW

Neutron ToF

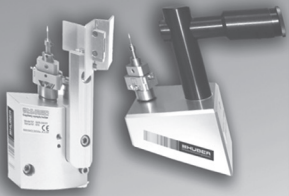
Traditional d-space, intensity, and hkl tables

Atomic coordinates or created CIF for import into WPF-Rietveld programs

Atom	Num	Wyckoff	Symmetry	x	y	z	SOF	ISP	AET
Sc	1	10d	6h	0.0762	0.1989	0.0	1.0	1.0	
Sc	2	4b	6h	0.0	0.5	0.25	1.0	1.0	
Fe	3	4b	6h	0.0	0.0	0.25	1.0	1.0	
Fe	4	8h	6h	0.1274	0.4274	0.0	1.0	1.0	

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Capillary
Sample Holder

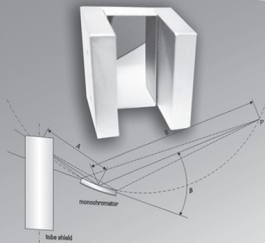


Diamond Anvil
Cell Holder



Capillary
Heater Device

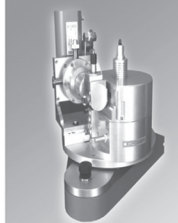
Johansson
Monochromator
Crystals



Diode Laser
Furnace



Low
Temperature
Device



Vertical Base
for Liquids/
Thin Films



Sample
Changer

Capillary
Boy



Plane Sample
Holder



Your Decision
for Precision

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